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Report No.: SZEM141100638703
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SAR Evaluation Report

Application No.: SZEM1411006387CR (SGS GZ No.:GZEM1411006134AV)
Applicant: WOOX Innovations Limited
Manufacturer: WOOX Innovations Limited
Factory: Foshan City Nanhai Commtech Technology Co., Ltd
Product Name: Bluetooth Headset
Model No.(EUT): SHB7250
Add Model No.: SHB7250/XX, SHB7250YY/XX(X=0 to 9, Y=A to Z)
Trade Mark: Philips
FCC ID: 2AANUSHB7250
Standards: 47 CFR Part 1.1307(2013)
47 CFR Part 2.1093 (2013)
KDB447498D01 General RF Exposure Guidance v05
Date of Receipt: 2014-11-21
Date of Test: 2014-11-26 to 2014-12-15
Date of Issue: 2014-12-21

Test Result :	PASS*
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* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Jack Zhang
EMC Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

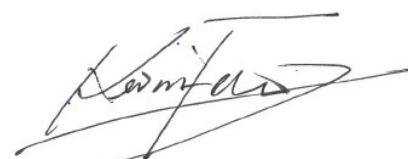
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2 Version

Revision Record				
Version	Chapter	Date	Modifier	Remark
00		2014-12-21		Original

Authorized for issue by:			
Tested By	 (Eric Fu) /Project Engineer	2014-12-15 Date	
Prepared By	 (Sade Luo) /Clerk	2014-12-21 Date	
Checked By	 (Kevin Feng) /Reviewer	2015-01-04 Date	



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4 General Information

4.1 Client Information

Applicant:	WOOX Innovations Limited
Address of Applicant:	5/F, Philips Electronics Building, No. 5 Science Park East Avenue, Hong Kong Science Park, Shatin, N.T., HONG KONG.
Manufacturer:	WOOX Innovations Limited
Address of Manufacturer:	5/F, Philips Electronics Building, No. 5 Science Park East Avenue, Hong Kong Science Park, Shatin, N.T., HONG KONG.
Factory:	Foshan City Nanhai Commtech Technology Co., Ltd
Address of Factory:	Yi Zhong, DaZhen, Da Li, Nan Hai District, FoShan City, Guangdong Province, P.R.C

4.2 General Description of EUT

Product Name:	Bluetooth Headset
Model No.:	SHB7250 (Only the model SHB7250 was tested, since the circuit design, PCB layout, electrical components used, internal wiring and functions were identical for the above models, XX just represent 00~99 to indicate the country version. YY(Y=A~Z) just represent the color version. SHB7250/XX & SHB7250YY/XX are same as SHB7250 except the model numbers indicate. Being sold to different countries.)
Trade Mark:	Philips
Operation Frequency:	2402MHz~2480MHz
Bluetooth Version:	BT 4.0 dual
Modulation Type:	For Classical mode:GFSK, $\pi/4$ DQPSK, 8DPSK For BLE mode:DSSS
Number of Channel:	For Classical mode:79 For BLE mode:40
Antenna Type:	Integral
Antenna Gain:	0dBi
Power Supply:	USB charge 3.7V Rechargeable Battery 120V SUPPLIED BY ADAPTOR



4.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch E&E Lab

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China
518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L2929)**

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **VCCI**

The 10m Semi-anechoic chamber and Shielded Room (7.5m x 4.0m x 3.0m) of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

- **FCC – Registration No.: 556682**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 556682.

- **Industry Canada (IC)**

Two 3m Semi-anechoic chambers of SGS-CSTC Standards Technical Services Co., Ltd. have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1 & 4620C-2.

4.5 Deviation from Standards

None.

4.6 Abnormalities from Standard Conditions

None.

4.7 Other Information Requested by the Customer

None.



5 SAR Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v05

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

5.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\frac{[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}]}{\leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}}$$

$f(\text{GHz})$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion



5.1.3 EUT RF Exposure

For Classical mode:

The Max Conducted Peak Output Power is 3.66dBm in highest channel(2.441GHz);

The best case gain of the antenna is 0dBi.

EIRP= 3.66dBm + 0dBi = 3.66dBm

3.66dBm logarithmic terms convert to numeric result is nearly 2.3227mW

According to the formula. calculate the EIRP test result:

$$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}]$$

General RF Exposure = $(2.3227\text{mW} / 5 \text{ mm}) \times \sqrt{2.441\text{GHz}} = 1.1339$ ①

SAR requirement:

S= 3.0

② ;

① < ②.

So the SAR report is not required.

For BLE mode:

The Max Conducted Peak Output Power is 1.43dBm in highest channel(2.440GHz);

The best case gain of the antenna is 0dBi.

EIRP= 1.43dBm + 0dBi = 1.43dBm

1.43dBm logarithmic terms convert to numeric result is nearly 1.3900mW

According to the formula. calculate the EIRP test result:

$$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}]$$

General RF Exposure = $(1.3900\text{mW} / 5 \text{ mm}) \times \sqrt{2.440\text{GHz}} = 0.4342$ ①

SAR requirement:

S= 3.0

② ;

① < ②.

So the SAR report is not required.